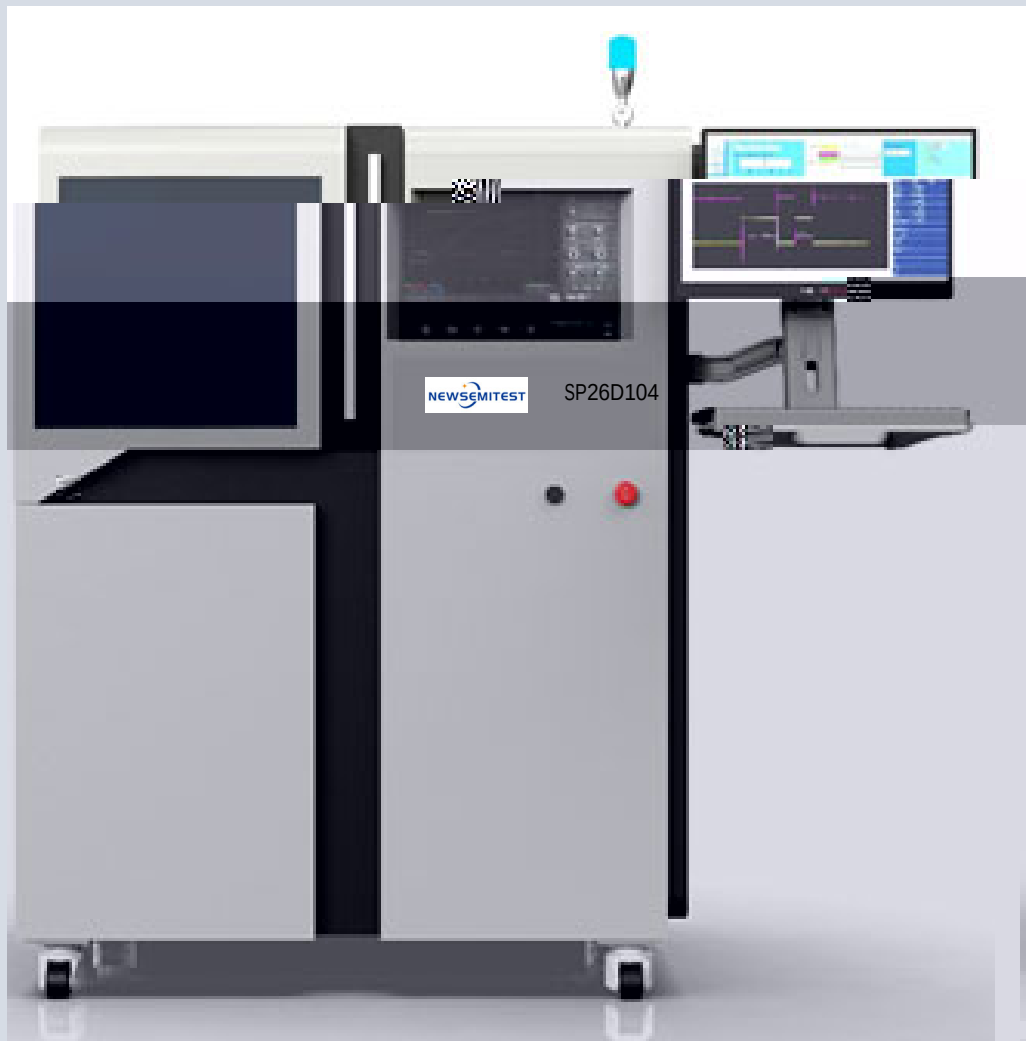


SP26D

Power Semiconductor Dynamic Test System

— — — — —



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SP26D ≠ χ $\sim$ ه پ $\text{”}\dot{\text{Q}}$ $\sim$ ن س^{B} D J $\sim$ $\frac{2}{3}$
 IEC60747-8/9 r JESD2 ^{8} ’ χ $\pm$ غ $\updownarrow$ r v ’ M
 r M غ b r $\pm$ r PCB ’ χ $\pm$ غ r
 r F Q p r ’ χ J LET2000D س J
 ج ’ ^{8} $\frac{2}{3}$ M غ r

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χ $\pm$ غ $\updownarrow$ Æ J $\text{”}\dot{\text{Q}}$ PC r r v r r r
 ’ O I M r SP26D ’ χ 12bit J ج ي
 س غ ^{8} J K ” r س J
 SiC/GaN J پ ج ’ r / r J ج $\text{”}\dot{\text{Q}}$ r
 غ ’H J K M r

M B D :

$\text{”}\dot{\text{Q}}$ ’H $\text{”}\dot{\text{Q}}$ 12 bit J ^{8}
 r J SiC/GAN
 ج ’ r / r پ J $\text{”}\dot{\text{Q}}$
 r ج ’ ”
 M $\pm$ SiC/GAN M
 ج J
 ج ’ N M
 M ج ’ O $\pm$

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غ 'H Ж Ĩ غ r ث ي غ r غ r

M Ж Ё / J MOSFET r IGBT

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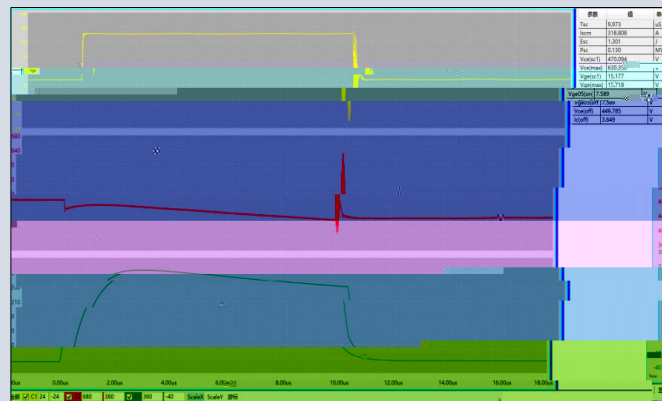
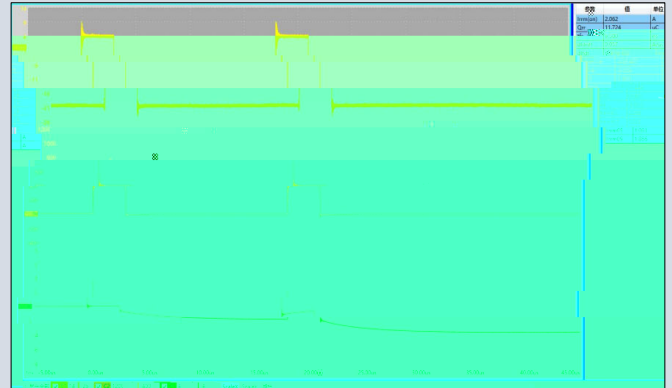
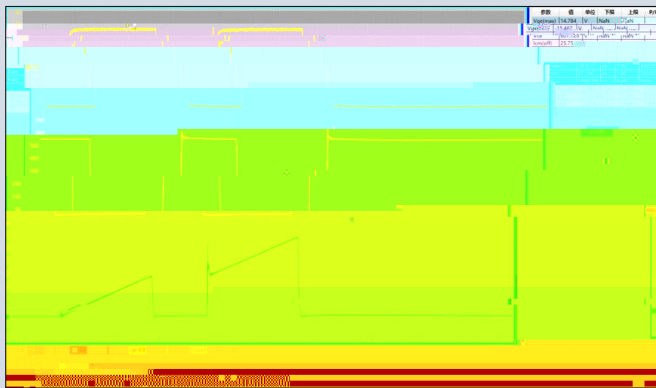
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SP26DD M

SP26DD

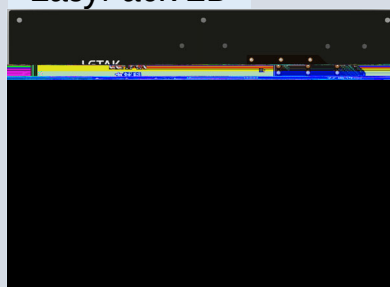


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EasyPack 1B



EasyPack 2B

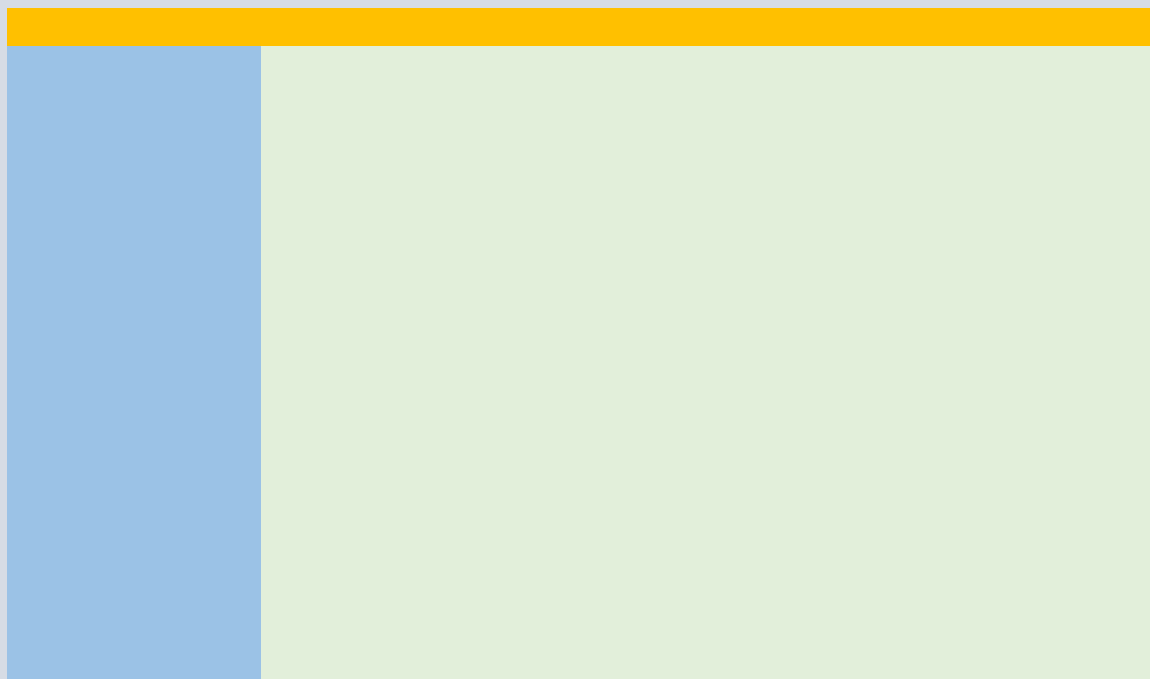


5kV



5kV

Ж ғ



SP26D Ж

PCB

Ж "

500MHz 1000MHz
1.5%
160 dB CMRR

↑ غ	گ غ	غ
' غ	Vge/Vgs	± U
	Vce/Vds	- U
	Vce/Vds pk	I U W
	Ic/Id pk	W
I غ	td(on)	±
	Tr	o
	Ton	±
	Eon	
	td(off)	I
	Tf	r
	Toff	I
	Eoff	I
	dv/dt	U 5
	di/dt	5
غ ث ي	Trr	ث ي
	Irr	ث ي
	Qrr	ث ي
	Err	ث ي
	Id vs t	ث ي
	Vsd	ل ث U
غ	di/dt	5
	Tsc	
	Iscm	س
	Esc	
	Psc	لا

